Application No.: 10/040709 Docket No.: SMQ-044

AMENDMENTS TO THE CLAIMS

1. (Currently Amended) In an electronic device, a method, comprising the steps of:

providing simulation output from a simulation of an electrical component, said simulation output containing information regarding a data signal and a clock signal;

providing an automated tool for analyzing the information in the simulation output regarding the data signal and the clock signal and for producing a report of results of the analysis;

receiving user-specified parameters at the tool; and applying the user-specified parameters to configure the analysis performed by the tool; and

performing the analysis of the simulation output with the tool to produce the report of the analysis.

- 2. (Original) The method of claim 1 further comprising the step of performing error checking on the simulation output to identify any errors in the simulation output.
- 3. (Original) The method of claim 1, wherein the report contains information regarding hold times of the data signal.
- 4. (Original) The method of claim 1, wherein the report contains information regarding setup times of the data signal.
- 5. (Original) The method of claim 1, wherein the report contains information regarding data jitter.
- 6. (Original) The method of claim 1, wherein the simulation output contains information regarding the data signal and the clock signal for a simulated time period and wherein the user-specified parameters include a specification of a portion of the simulated time period to which the analysis is to be applied.
- 7. (Original) The method of claim 1, wherein the user-specified parameters include a specification of a voltage reference window extending from a logically high reference voltage to a logically low reference voltage.
- 8. (Original) The method of claim 1, wherein the data signal is single-ended.

Application No.: 10/040709 Docket No.: SMQ-044

9. (Original) The method of claim 1, wherein the data signal is differential.

10. (Currently Amended) A storage medium for use with an electronic device, said medium holding instructions executable by the electronic device for performing a method, said method comprising the steps of:

receiving user-specified parameters regarding an analysis of <u>a</u> simulation output from a simulation of an electrical component, said simulation output containing information regarding a data signal and a clock signal.

applying the user-specified parameters to configure the analysis; and performing the analysis of the simulation output to produce a report of the analysis.

- 11. (Original) The storage medium of claim 10, wherein the method further comprises the step of performing error checking on the simulation output to identify errors in the simulation output.
- 12. (Original) The storage medium of claim 10, wherein the report contains information regarding hold times of the data signal.
- 13. (Original) The storage medium of claim 10, wherein the report contains information regarding setup times of the data signal.
- 14. (Original) The storage medium of claim 10, wherein the report contains information regarding data jitter.
- 15. (Original) The storage medium of claim 10, wherein the simulation output contains information regarding the data signal and the clock signal for a simulated time period and wherein the user-specified parameters include a specification of a portion of the simulated time period to which the analysis is to be applied.
- 16. (Original) The storage medium of claim 10, wherein the user-specified parameters include a specification of a voltage reference window extending from a logically high reference voltage to a logically low reference voltage.
- 17. (Original) The storage medium of claim 10, wherein the data signal is single-ended.

Application No.: 10/040709 Docket No.: SMQ-044

18. (Original) The storage medium of claim 10, wherein the data signal is differential.

19. (Original) In an electronic device, a method, comprising the steps of:

providing results of simulation of an electrical component wherein said results contain waveform representations of a data signal and a clock signal over a simulated time period; and

with an automated analysis facility, processing the results of the simulation to identify data jitter for the data signal.

- 20. (Original) The method of claim 19, wherein the method further comprises the step of producing a report containing information regarding the data jitter for the data signal.
- 21. (Original) The method of claim 19, wherein the step of processing the results processes the results for only a portion of the simulated time period.
- 22. (Original) A storage medium holding instructions of an automated analysis facility that are executable by an electronic device for performing a method, said method comprising the steps of:

providing results of simulation of an electrical component wherein said results contain waveform representations of a data signal and a clock signal over a simulated time period; and

with an automated analysis facility, processing the results of the simulation to identify data jitter for the data signal.